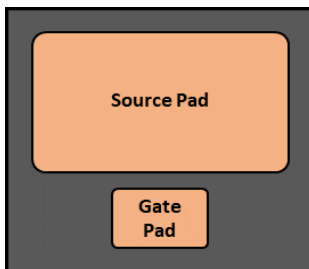


DATASHEET

UF3N120140



Part Number	Package
UF3N120140	Undiced wafer
UF3N120140Z	Die on tape



1200V-142mΩ SiC Normally-on JFET

Rev. A, February 2022

Description

UnitedSiC offers the high-performance G3 SiC normally-on JFET transistors. This series exhibits ultra-low on resistance ($R_{DS(ON)}$) and gate charge (Q_G) allowing for low conduction and switching loss. The device normally-on characteristics with low $R_{DS(ON)}$ at $V_{GS} = 0\text{ V}$ is also ideal for current protection circuits without the need for active control, as well as for cascode operation.

Features

- ♦ Typical on-resistance $R_{DS(on),typ}$ of 142mΩ
- ♦ Voltage controlled
- ♦ Maximum operating temperature of 175°C
- ♦ Extremely fast switching not dependent on temperature
- ♦ Low gate charge
- ♦ Low intrinsic capacitance
- ♦ RoHS compliant

Typical applications

- ♦ Over Current Protection Circuits
- ♦ DC-AC Inverters
- ♦ Switch mode power supplies
- ♦ Power factor correction modules
- ♦ Motor drives
- ♦ Induction heating

Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		1200	V
Gate-source voltage	V_{GS}	DC	-20 to +3	V
		AC ¹	-30 to +20	V
Continuous drain current ^{2,3}	I_D	$T_C = 25^\circ\text{C}$	18.7	A
		$T_C = 100^\circ\text{C}$	14	A
Pulsed drain current ^{3,4}	I_{DM}	$T_C = 25^\circ\text{C}$	38	A
Maximum junction temperature ⁵	$T_{J,max}$		175	$^\circ\text{C}$
Operating and storage temperature	T_J, T_{STG}		-55 to 175	$^\circ\text{C}$

1. +20V AC rating applies for turn-on pulses <200ns applied with external $R_G > 1\Omega$.

2. Limited by $T_{J,max}$

3. Assumes a maximum junction-to-case thermal resistance of 0.9°C/W

4. Pulse width t_p limited by $T_{J,max}$

5. Package limited

Electrical Characteristics ($T_J = +25^\circ\text{C}$ unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Drain-source breakdown voltage	BV_{DS}	$V_{GS} = -20\text{V}, I_D = 1\text{mA}$	1200			V
Total drain leakage current	I_{DSS}	$V_{DS} = 1200\text{V}, V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		1.4	60	μA
		$V_{DS} = 1200\text{V}, V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		7		
Total gate leakage current	I_{GSS}	$V_{GS} = -20\text{V}, T_J = 25^\circ\text{C}$		0.2	15	μA
		$V_{GS} = -20\text{V}, T_J = 175^\circ\text{C}$		1.4		μA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS} = 2\text{V}, I_D = 14\text{A}, T_J = 25^\circ\text{C}$		123		m Ω
		$V_{GS} = 0\text{V}, I_D = 14\text{A}, T_J = 25^\circ\text{C}$		142	180	
		$V_{GS} = 2\text{V}, I_D = 14\text{A}, T_J = 175^\circ\text{C}$		303		
		$V_{GS} = 0\text{V}, I_D = 14\text{A}, T_J = 175^\circ\text{C}$		360		
Gate threshold voltage	$V_{G(th)}$	$V_{DS} = 5\text{V}, I_D = 17.5\text{mA}$	-11.3	-8.7	-6.7	V
Gate resistance	R_G	$f = 1\text{MHz}$, open drain		2.4		Ω

Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Input capacitance	C_{iss}	$V_{DS}=100V, V_{GS}=-20V$ $f=100kHz$		444		pF
Output capacitance	C_{oss}			49		
Reverse transfer capacitance	C_{rss}			45		
Effective output capacitance, energy related	$C_{oss(er)}$	$V_{DS}=0V$ to $800V$, $V_{GS}=-20V$		29		pF
C_{oss} stored energy	E_{oss}	$V_{DS}=800V, V_{GS}=-20V$		9.3		μJ
Total gate charge	Q_G	$V_{DS}=800V, I_D=14A$, $V_{GS} = -18V$ to $0V$		55		nC
Gate-drain charge	Q_{GD}			34		
Gate-source charge	Q_{GS}			7		
Turn-on delay time	$t_{d(on)}$	$V_{DS}=800V, I_D=14A$, Gate Driver $= -18V$ to $0V$, $R_G=1\Omega$, Inductive Load, FWD: UJ3D1210TS $T_J=25^\circ C$		7		ns
Rise time	t_r			14		
Turn-off delay time	$t_{d(off)}$			11		
Fall time	t_f			10		
Turn-on energy	E_{ON}			127		μJ
Turn-off energy	E_{OFF}	$V_{DS}=800V, I_D=14A$, Gate Driver $= -18V$ to $0V$, $R_G=1\Omega$, Inductive Load, FWD: UJ3D1210TS $T_J=150^\circ C$		44		
Total switching energy	E_{TOTAL}			171		
Turn-on delay time	$t_{d(on)}$			6		ns
Rise time	t_r			13		
Turn-off delay time	$t_{d(off)}$			10		
Fall time	t_f			8		
Turn-on energy	E_{ON}			119		μJ
Turn-off energy	E_{OFF}			31		
Total switching energy	E_{TOTAL}			150		

Typical Performance Diagrams

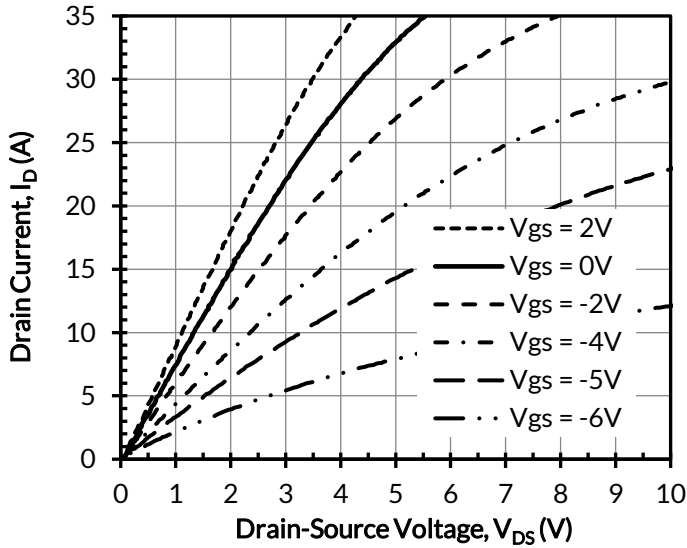


Figure 1. Typical output characteristics at $T_j = -55^\circ\text{C}$, $t_p < 250\mu\text{s}$

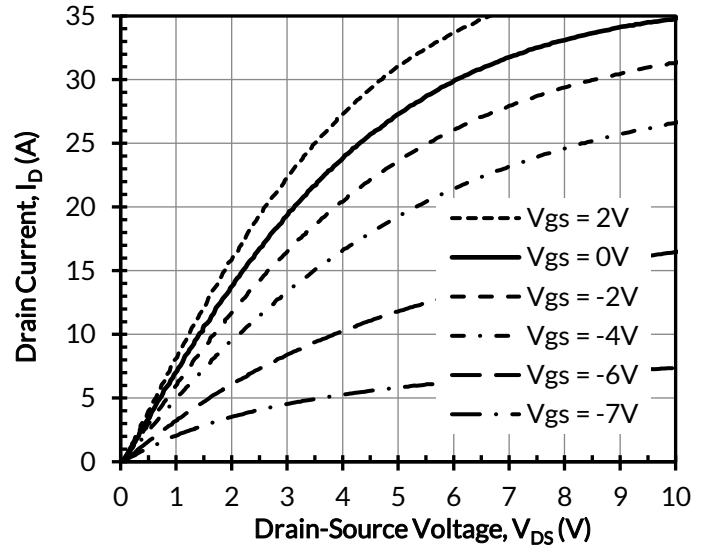


Figure 2. Typical output characteristics at $T_j = 25^\circ\text{C}$, $t_p < 250\mu\text{s}$

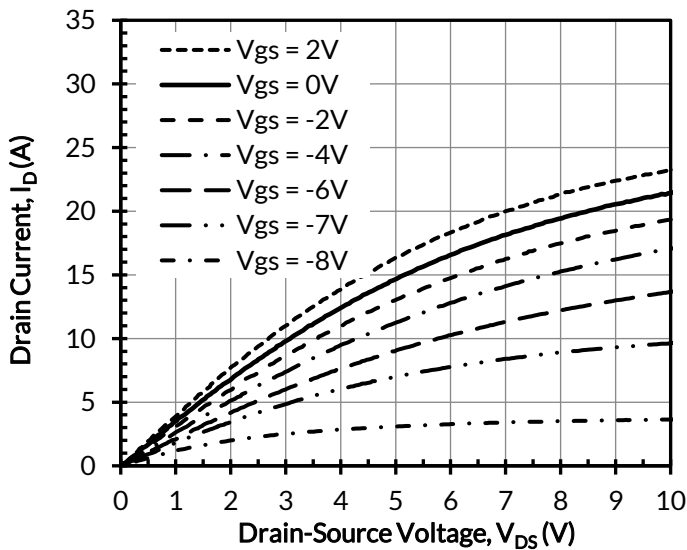


Figure 3. Typical output characteristics at $T_j = 175^\circ\text{C}$, $t_p < 250\mu\text{s}$

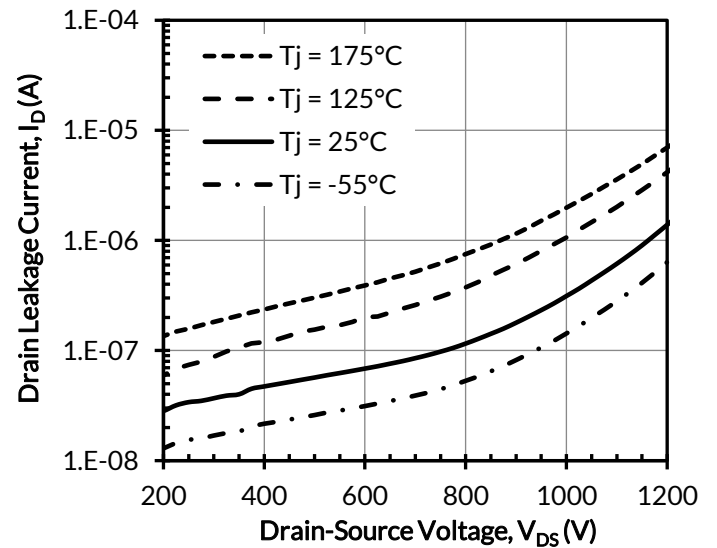


Figure 4. Typical drain-source leakage at $V_{GS} = -20\text{V}$

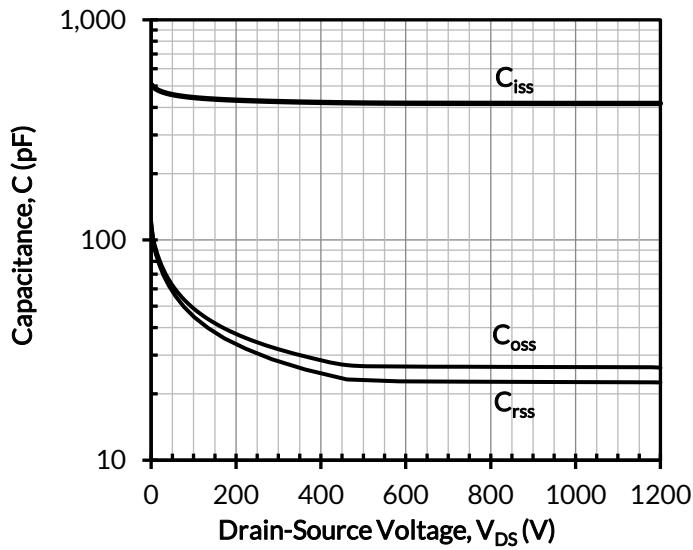


Figure 5. Typical capacitances at $f = 100\text{kHz}$ and $V_{GS} = -20\text{V}$

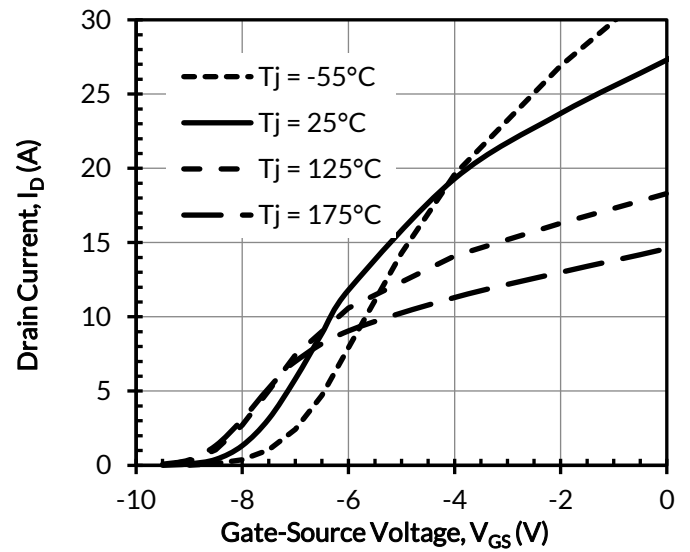


Figure 6. Typical transfer characteristics at $V_{DS} = 5\text{V}$

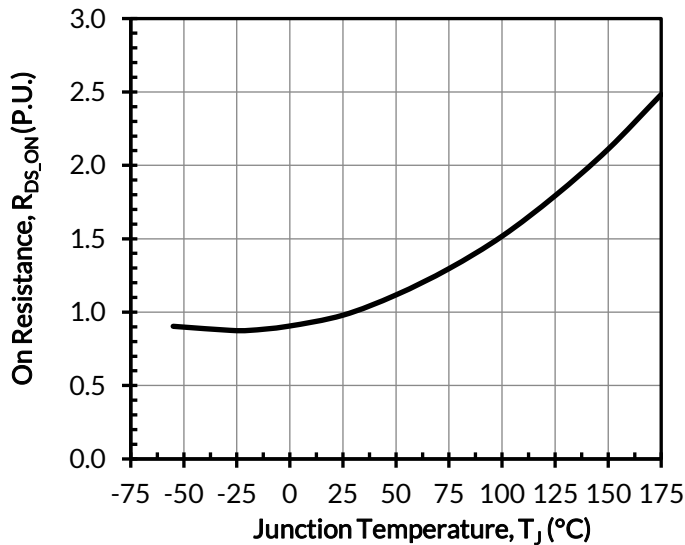


Figure 7. Normalized on-resistance vs. temperature at $V_{GS} = 0\text{V}$ and $I_D = 14\text{A}$

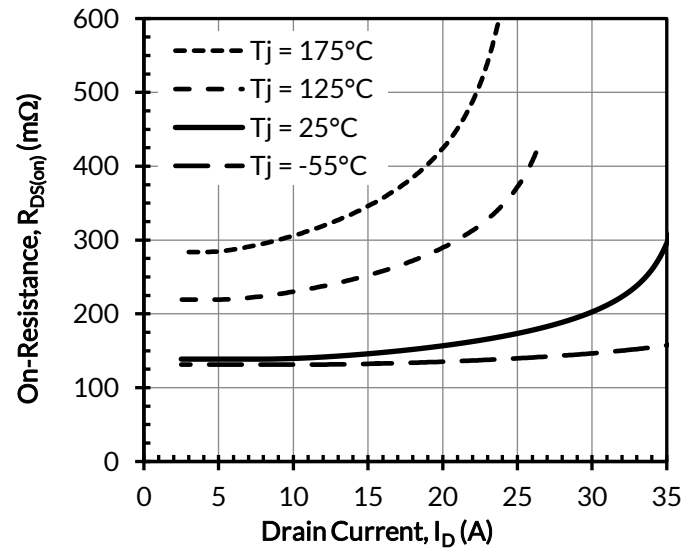


Figure 8. Typical drain-source on-resistances at $V_{GS} = 0\text{V}$

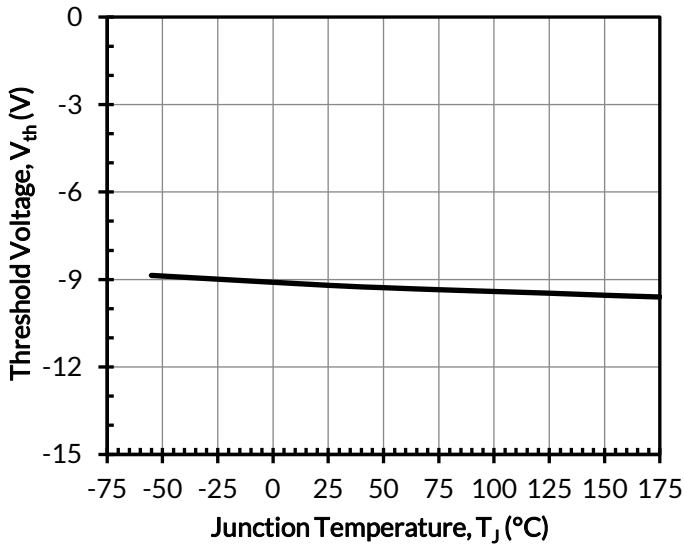


Figure 9. Threshold voltage vs. junction temperature at $V_{DS} = 5V$ and $I_D = 17.5mA$

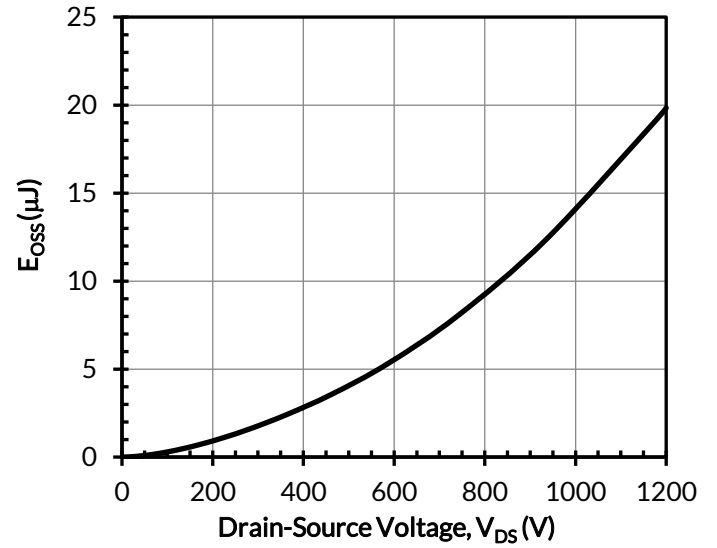


Figure 10. Typical stored energy in C_{OSS} at $V_{GS} = -20V$

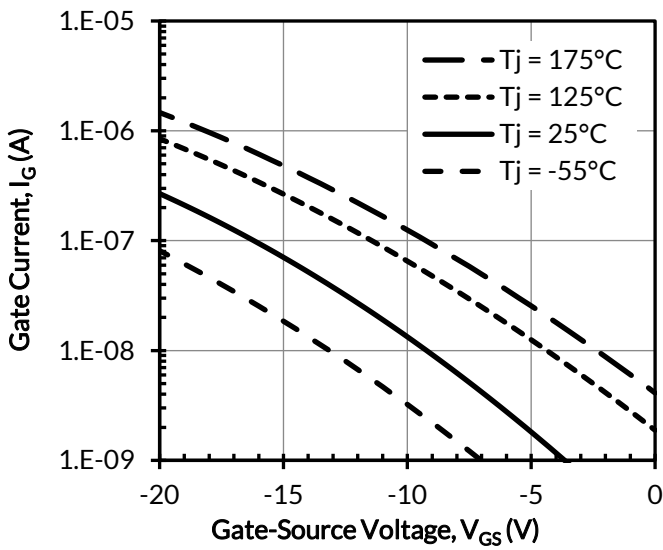


Figure 11. Typical gate leakage at $V_{DS} = 0V$

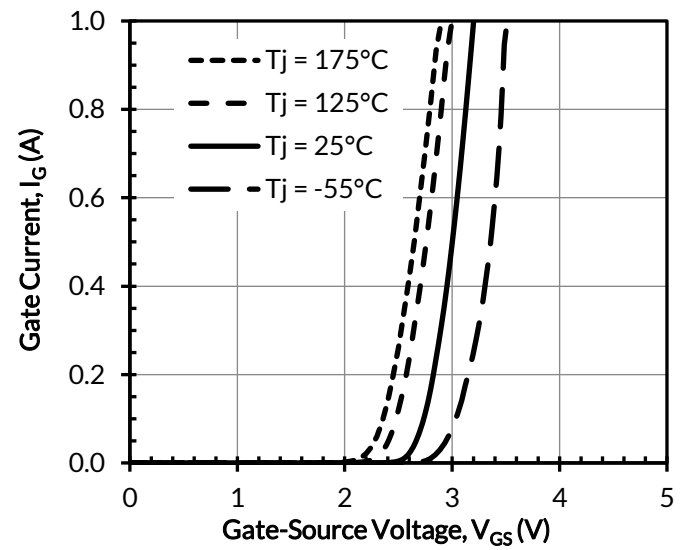


Figure 12. Typical gate forward current at $V_{DS} = 0V$

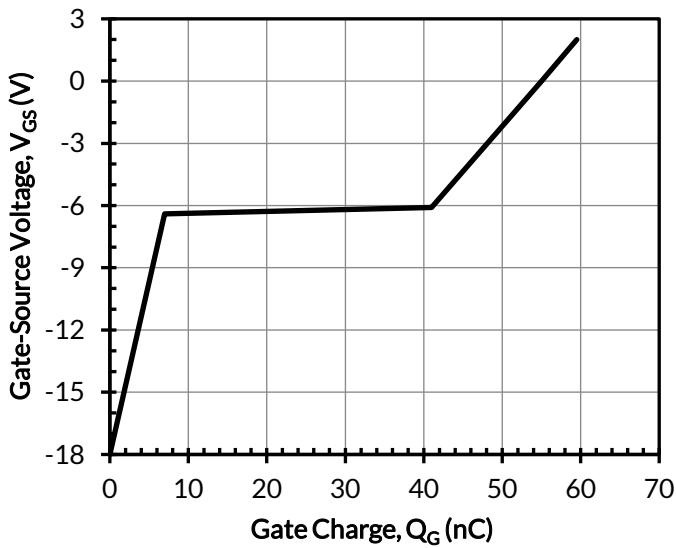


Figure 13. Typical gate charge at $V_{DS} = 800V$ and $I_D = 14A$

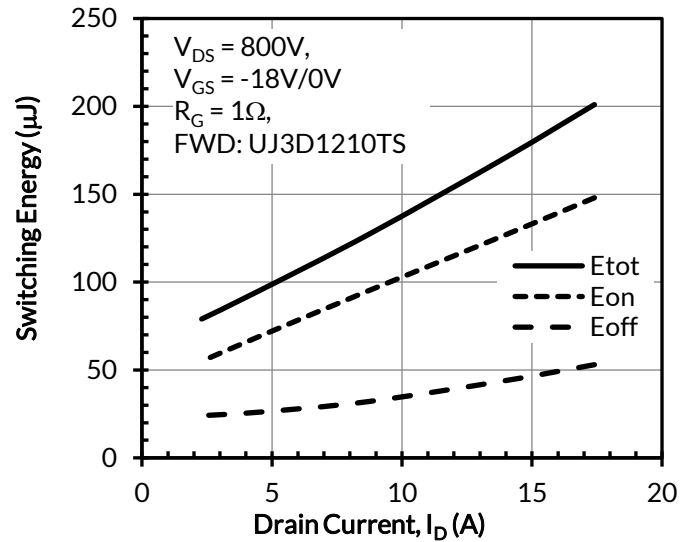


Figure 14. Clamped inductive switching energy vs. drain current at $T_J = 25^\circ C$

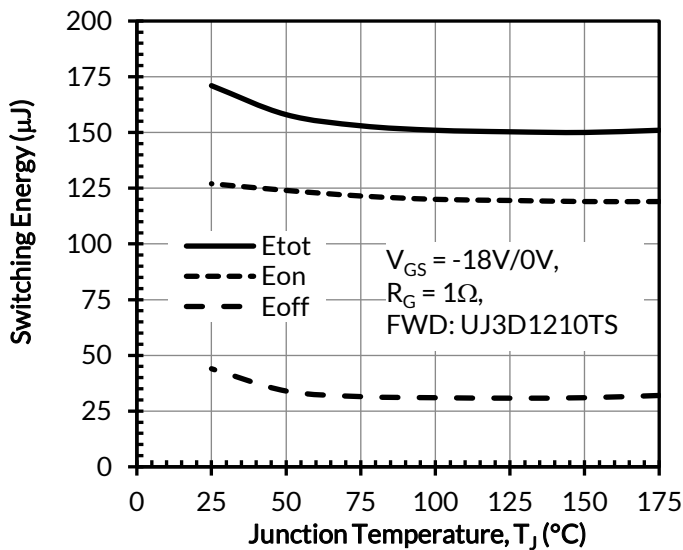


Figure 15. Clamped inductive switching energy vs. junction temperature at $V_{DS} = 800V$ and $I_D = 14A$

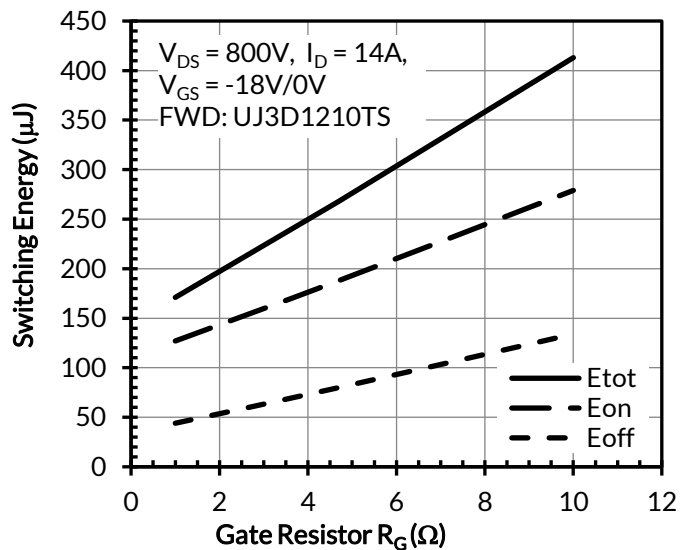
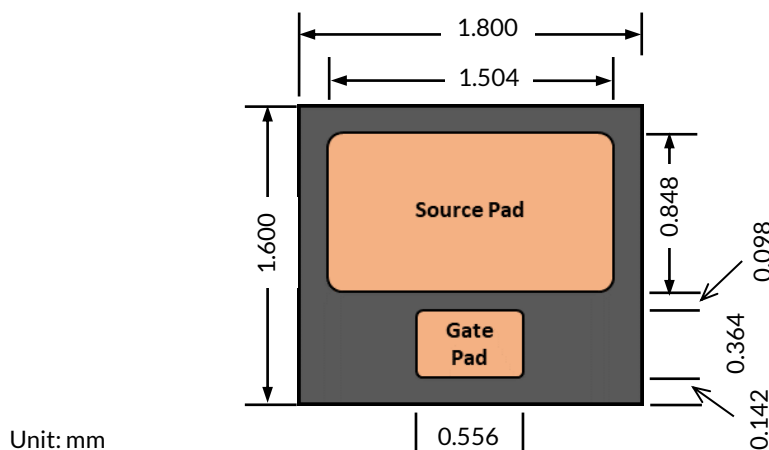


Figure 16. Clamped inductive switching energy vs. gate resistor R_G at $T_J = 25^\circ C$

Mechanical Characteristics

Parameter	Typical Value	Units
Die dimensions with scribe line (L x W)	1.800 x 1.600	mm
Scribe line width	80	μm
Source pad metal dimensions (L x W)	1.504 x 0.848	mm
Gate pad metal dimensions (L x W)	0.556 x 0.364	mm
Source metallization (AlCu)	5	μm
Gate metallization (AlCu)	5	μm
Backside drain metallization (Ti/Ni/Ag)	0.1/0.2/1	μm
Frontside passivation	Polyimide	
Die thickness	150	μm
Wafer size	150	mm
Gross die per wafer	4939	

Chip Dimensions



Important notice

The information contained herein is believed to be reliable; however, Qorvo makes no warranties regarding the information contained herein and assumes no responsibility or liability whatsoever for the use of the information contained herein. All information contained herein is subject to change without notice. Customers should obtain and verify the latest relevant information before placing orders for Qorvo products. The information contained herein or any use of such information does not grant, explicitly or implicitly, to any party any patent rights, licenses, or any other intellectual property rights, whether with regard to such information itself or anything described by such information. THIS INFORMATION DOES NOT CONSTITUTE A WARRANTY WITH RESPECT TO THE PRODUCTS DESCRIBED HEREIN, AND QORVO HEREBY DISCLAIMS ANY AND ALL WARRANTIES WITH RESPECT TO SUCH PRODUCTS WHETHER EXPRESS OR IMPLIED BY LAW, COURSE OF DEALING, COURSE OF PERFORMANCE, USAGE OF TRADE OR OTHERWISE, INCLUDING THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Without limiting the generality of the foregoing, Qorvo products are not warranted or authorized for use as critical components in medical, life-saving, or life-sustaining applications, or other applications where a failure would reasonably be expected to cause severe personal injury or death.